

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/587,315 YAMADA ET AL.	
		Examiner	Art Unit JUAN E. VAUGHN II	1795 Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0224281 A1	12-2003	Ishizuka et al.	430/157
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NON-PATENT DOCUMENTS

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